
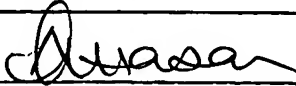


INFORMATION DISCLOSURE CITATION				Attorney Docket No.: 041514-5283		Application No.: 10/804,193	
<div style="text-align: center;">  <p>PTO Form-1449</p> </div>				Applicant(s): Ikuo ARATA et al.		PAGE 1 OF 1	
				Filing Date: March 19, 2004		Group: <u>2873</u> <i>Unassigned</i>	
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M.H	JP 2002-189000 (corresponds to USP Nos. 6,475,398 B2, 6,608,359 B2 & 6,656,029 B2)	July 5, 2002	Japan			Abstract	
	JP 05-157701	June 25, 1993	Japan	✓	—	Abstract	
	JP 11-003534	January 6, 1999	Japan	✓	✓	Abstract	
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	JP 7-18806 (corresponds to USP Nos. 5,208,648 & 5,220,403)	March 6, 1995	Japan	✓	—	Abstract	
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M.H	Arata et al., "Photoemission and OBIRCH Analysis with Solid Immersion Lens (SIL)", ISTFA, (2003), pp. 1-20.						
M.H	"Conference Proceedings from the 29th International Symposium for Testing and Failure Analysis", ISTFA, (2003), pp. 325-329.						
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				3/24/2005			
Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication.							